

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki, et al. Art Unit : 2826  
Serial No. : 10/727,651 Examiner : Ahmed N. Sefer  
Filed : December 5, 2003 Conf. No. : 8958  
Title : THIN FILM TRANSISTORS AND SEMICONDUCTOR DEVICE

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

REQUEST FOR INITIALED PTO FORM 1449

Upon reviewing the file, applicants noted that they have not received a complete initialed copy of the enclosed PTO Form 1449 that accompanied an information disclosure statement filed with the application on December 5, 2003. The attached PTO-1449 was returned signed, however, the references identified as Desig. ID "BA", "BP" and "BQ" were not initialed and it is not clear as to whether the Examiner considered the references.

Please note that under 35 USC §120, this application relies on the earlier filing date of application serial number 09/874,204, filed on June 6, 2001. The references were submitted to and/or cited by the Office in the prior application and, therefore, were not provided in this application.

Thus, we respectfully request that the examiner initial and return this form as soon as possible. Note, applicants must pay the issue fee by September 9, 2007, so the examiner's prompt attention to this matter would be appreciated.

Respectfully submitted,

Date: 8/21/07

  
\_\_\_\_\_  
Roberto J. Devoto  
Reg. No. 55,108

Customer No. 26171  
Fish & Richardson P.C.  
1425 K Street, N.W. - 11th Floor  
Washington, DC 20005-3500  
(202) 783-5070 telephone  
(202) 783-2331 facsimile  
/adt  
40439261.doc

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-051002	Application No. 10/727,651
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Shunpei Yamazaki, et al.		
		Filing Date December 5, 2003	Group Art Unit 2826	

**UPDATED VERSION****U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,766,477	08/23/1988	Nakagawa, et al.			
	AB	5,643,826	07/01/1997	Ohtani, et al.			
	AC	5,923,962	07/13/1999	Ohtani, et al.			
	AD	5,943,560	08/24/1999	Chang, et al.			
	AE	5,977,560	11/02/1999	Banerjee, et al.			
	AF	6,087,679	07/2000	Yamazaki, et al.			
	AG	US 2002/0043662	04/18/2002	Yamazaki, et al.			
	AH	US 2002/0038889	04/04/2002	Yamazaki, et al.			
	AI	US 2002/0014625	02/07/2002	Asami, et al.			
	AJ	US 2002/0008286	01/24/2002	Yamazaki, et al.			
	AK	US 2002/0040981	04/2002	Yamazaki, et al.			
	AL	US 2003/0001159	01/02/2003	Ohtani, et al.			
	AM	5,162,933	11/10/1992	Kakuda, et al.			
	AN	5,304,407	04/19/1994	Hayashi, et al.			
	AO	5,602,424	02/1997	Tsubouchi, et al.			
	AP	5,686,980	11/11/1997	Hirayama, et al.			
	AQ	5,932,893	08/03/1999	Miyanaga, et al.			
	AR	6,107,639	08/22/2000	Yamazaki, et al.			
	AS	6,107,654	08/22/2000	Yamazaki, et al.			
	AT	6,180,957	01/30/2001	Miyasaka, et al.			
	AU	6,285,042	09/04/2001	Ohtani, et al.			
	AV	6,307,214	10/23/2001	Ohtani, et al.			
	AW	6,307,220	10/23/2001	Yamazaki			
	AX	6,335,541	01/01/2002	Ohtani, et al.			
	AY	6,348,368	02/19/2002	Yamazaki, et al.			
	AZ	6,452,211	09/17/2002	Ohtani, et al.			

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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				Filing Date December 5, 2003	Group Art Unit 2826		

	BA	6,495,886	12/17/2002	Yamazaki, et al.			06/13/2002
	BB						

<b>Foreign Patent Documents or Published Foreign Patent Applications</b>							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes      No
	BC	8-78329	03/22/1996	Japan			Abstract
	BD	7-130652	05/19/1995	Japan			Abstract
	BE	TW 251379	07/11/1995	Taiwan			Full
	BF	TW 310478	07/11/1997	Taiwan			Abstract
	BG	JP 11-345767	12/1999	Japan			Abstract
	BH	JP 4-349619	12/1992	Japan			Abstract
	BI	EP 984317	03/2000	Europe			In English
	BJ	02-219234	08/31/1990	Japan			Abstract
	BK	11-204434	07/30/1999	Japan			Abstract
	BL	11-284198	10/15/1999	Japan			Abstract
	BM	11-307783	11/05/1999	Japan			Abstract
	BN	EP 510969	10/28/1992	Europe			In English
	BO						

<b>Other Documents (include Author, Title, Date, and Place of Publication)</b>		
Examiner Initial	Desig. ID	Document
	BP	R. Ishihara et al., "Micro Texture Analysis Of Location Controlled Large Si Grain Formed by Exciter-Laser Crystallization Method"; <i>AMLCD '99 Digest of Technical Papers 1999 Tokyo, Japan</i> ; pp. 99-102; 1999
	BQ	Seok-Woon Lee et al.; "Low Temperature Poly-Si Thin-Film Transistor Fabrication by Metal-Induced Lateral Crystallization"; <i>IEEE Electron Device Letters, Vol. 17, No. 4</i> , pp. 160-162; April 1996
	BR	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	